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PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

10053970

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**APPLICANTS: Jacob Michael; Rohr Thomas; 3E: 201 3 NGUYEN, VICT					
**CONTINUING DATA VERIFIED:					
** FOREIGN APPLICATIONS VERIFIED: GERMANY 101 02 432.0 01/19/2001					
PG-PUB <input type="checkbox"/> DO NOT PUBLISH <input type="checkbox"/>		RESCIND <input type="checkbox"/>			
Foreign priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no 35 USC 119 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no Verified and Acknowledged Examiners's initials				ATTORNEY DOCKET NO MUH-12050	
TITLE : Test circuit for an analog measurement of bit line signals of ferroelectric memory cells <small>U.S. DEPT. OF COMM. / PAT. & TM. PTO-436L (Rev. 12-94)</small>					

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Assistant Examiner	Total Claims Print Claim for O.G.
ISSUE FEE		Primary Examiner	DRAWING
Amount Due	Date Paid		Sheets Drwg. Figs. Drwg. Print Fig.
<input type="checkbox"/> TERMINAL DISCLAIMER		PREPARED FOR ISSUE Application Examiner	
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